



# N-Channel Enhancement MOSFET

VDS= 60V, ID= 20A



## DESCRIPTION

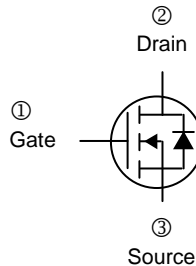
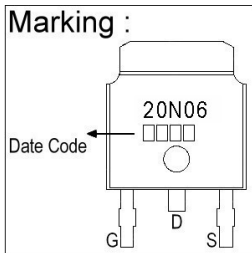
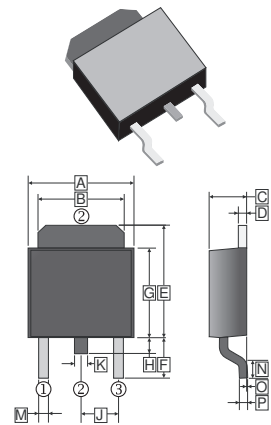
The YS20N06D is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent  $R_{DS(ON)}$  and gate charge for most of the synchronous buck converter applications.

The YS20N06D meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

## FEATURES

- Advanced high cell density Trench technology
- Excellent CdV/dt effect decline
- Green Device Available
- Super Low Gate Charge
- 100% EAS Guaranteed

TO-252(D-Pack)



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	6.35	6.90	J	2.336	REF.
B	4.95	5.53	K	0.89	REF.
C	2.10	2.50	M	0.45	1.14
D	0.665 Typ.		N	1.55 Typ.	
E	6.0	7.5	O	0	0.13
F	2.90 REF.		P	0.58 REF.	
G	5.40	6.40			
H	0.60	1.20			

## Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>1</sup>	$I_D @ T_C=25^\circ C$	20	A
Continuous Drain Current <sup>1</sup>	$I_D @ T_C=100^\circ C$	13	A
Pulsed Drain Current <sup>1,2</sup>	$I_{DM}$	40	A
Total Power Dissipation <sup>4</sup>	$P_D @ T_C=25^\circ C$	31.3	W
	$P_D @ T_A=25^\circ C$	2	W
Single Pulse Avalanche Energy, $L=0.1mH^3$	$E_{AS}$	22	mJ
Single Pulse Avalanche Current, $L=0.1mH^3$	$I_{AS}$	21	A
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 ~ +150	$^\circ C$

## Thermal Data

Parameter	Symbol	Conditions	Max. Value	Unit
Thermal Resistance Junction-ambient <sup>1</sup>	$R_{\theta JA}$	Steady State	62.5	$^\circ C/W$
Thermal Resistance Junction-case <sup>1</sup>	$R_{\theta JC}$	Steady State	4	$^\circ C/W$

# DEVICE CHARACTERISTICS

## YS20N06D

### Electrical Characteristics (T<sub>j</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	60	-	-	V	V <sub>GS</sub> =0, I <sub>D</sub> =250uA
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.2	-	2.5	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA
Forward Transconductance	g <sub>fs</sub>	-	25	-	S	V <sub>DS</sub> =5V, I <sub>D</sub> =15A
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±20V
Drain-Source Leakage Current(T <sub>j</sub> =25°C)	I <sub>DSS</sub>	-	-	1	uA	V <sub>DS</sub> =48V, V <sub>GS</sub> =0
Drain-Source Leakage Current(T <sub>j</sub> =55°C)		-	-	5	uA	V <sub>DS</sub> =48V, V <sub>GS</sub> =0
Static Drain-Source On-Resistance <sup>2</sup>	R <sub>DS(ON)</sub>	-	33	40	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =15A
		-	41	48		V <sub>GS</sub> =4.5V, I <sub>D</sub> =8A
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	-	19	-	nC	I <sub>D</sub> =15A V <sub>DS</sub> =48V V <sub>GS</sub> =10V
Gate-Source Charge	Q <sub>gs</sub>	-	2.5	-		
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	-	5	-		
Turn-on Delay Time <sup>2</sup>	T <sub>d(on)</sub>	-	2.8	-	ns	V <sub>DD</sub> =30V I <sub>D</sub> =15A V <sub>GS</sub> =10V R <sub>G</sub> =3.3Ω
Rise Time	T <sub>r</sub>	-	16.6	-		
Turn-off Delay Time	T <sub>d(off)</sub>	-	21.2	-		
Fall Time	T <sub>f</sub>	-	5.6	-		
Input Capacitance	C <sub>iss</sub>	-	1027	-	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =15V f=1.0MHz
Output Capacitance	C <sub>oss</sub>	-	65	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	46	-		
Gate Resistance	R <sub>g</sub>	-	2.5	-	Ω	f=1.0MHz

### Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy <sup>5</sup>	EAS	7.2	-	-	mJ	V <sub>DD</sub> =25V, L=0.1mH, I <sub>AS</sub> =12A

### Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Diode Forward Voltage <sup>2</sup>	V <sub>SD</sub>	-	-	1.2	V	I <sub>S</sub> =15A, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
Continuous Source Current <sup>1,6</sup>	I <sub>S</sub>	-	-	20	A	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current
Pulsed Source Current <sup>2,6</sup>	I <sub>SM</sub>	-	-	40	A	
Reverse Recovery Time	t <sub>rr</sub>	-	12.2	-	ns	I <sub>F</sub> =15A, di/dt=100A/μs,
Reverse Recovery Charge	Q <sub>rr</sub>	-	7.3	-	nC	T <sub>J</sub> =25°C

Notes: 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.

3. The EAS data shows Max. rating. The test condition is V<sub>DD</sub>=25V, V<sub>GS</sub>=10V, L=0.1mH, I<sub>AS</sub>=21A.

4. The power dissipation is limited by 150°C junction temperature.

5. The Min. value is 100% EAS tested guarantee.

6. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

# DEVICE CHARACTERISTICS

## YS20N06D

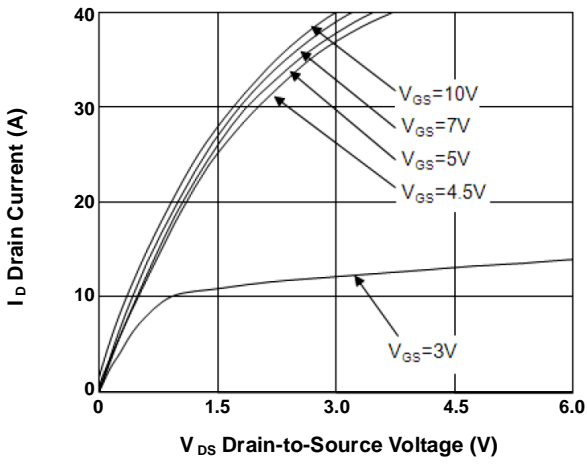


Fig.1 Typical Output Characteristics

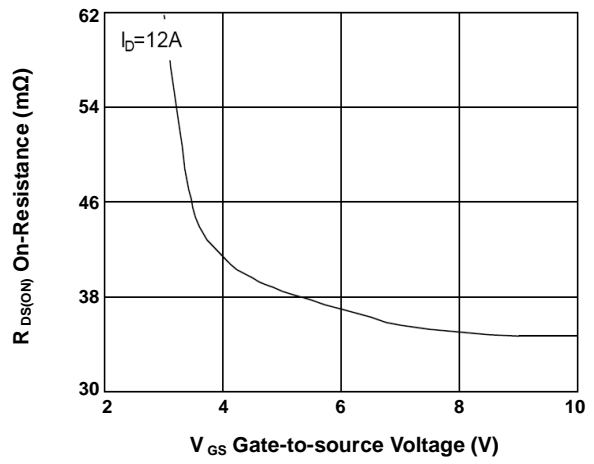


Fig.2 On-Resistance vs. G-S Voltage

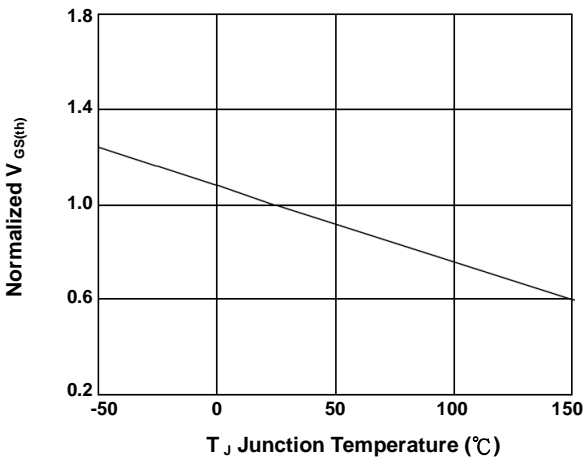


Fig.3 Normalized  $V_{GS(th)}$  vs.  $T_J$

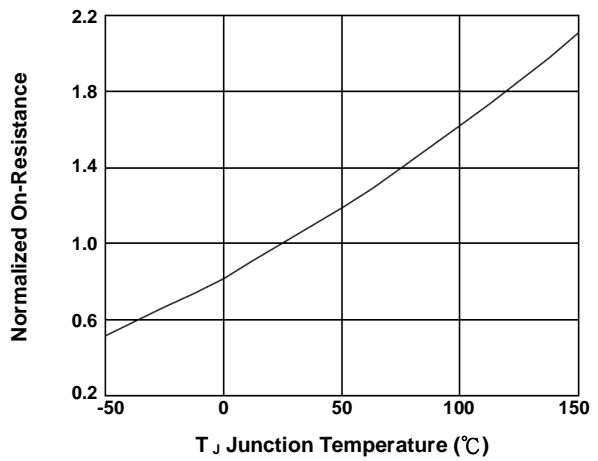


Fig.4 Normalized  $R_{DS(on)}$  vs.  $T_J$

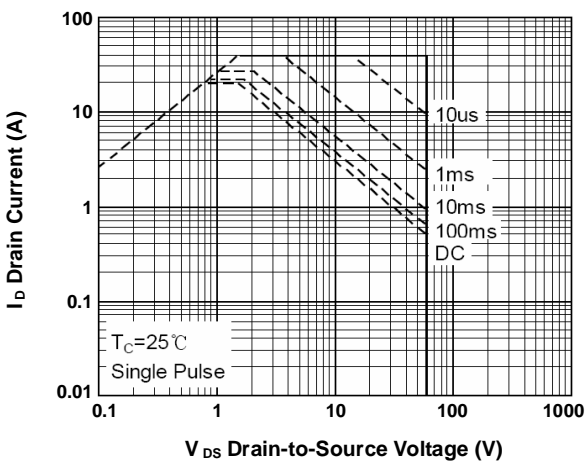


Fig.5 Safe Operating Area

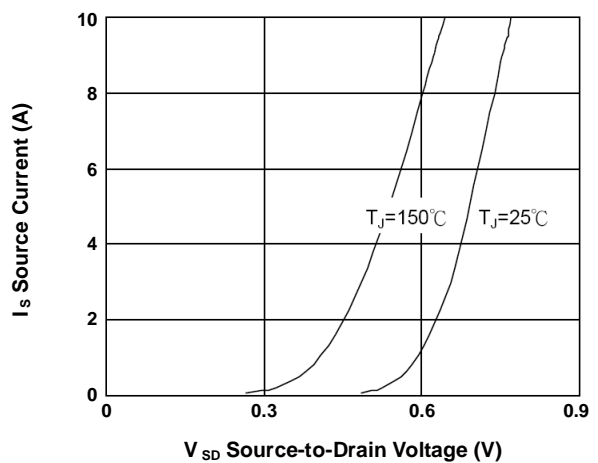


Fig.6 Forward Characteristics of Reverse

# DEVICE CHARACTERISTICS

## YS20N06D

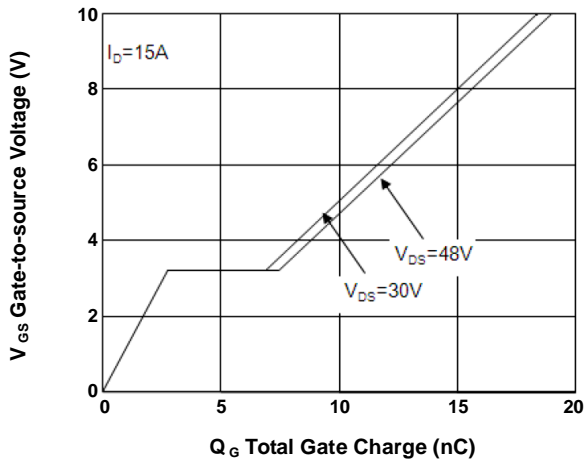


Fig.7 Gate Charge Characteristics

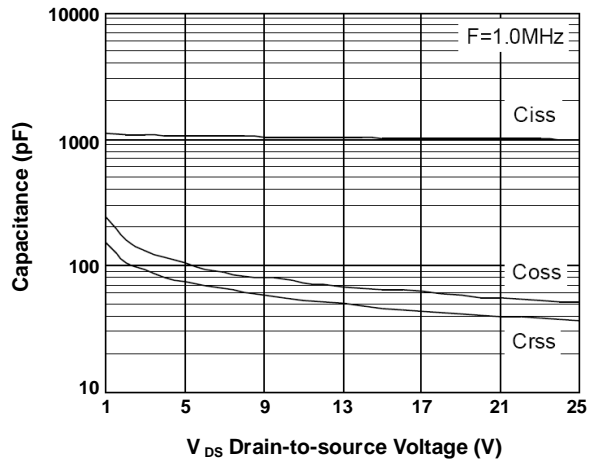


Fig.8 Capacitance Characteristics

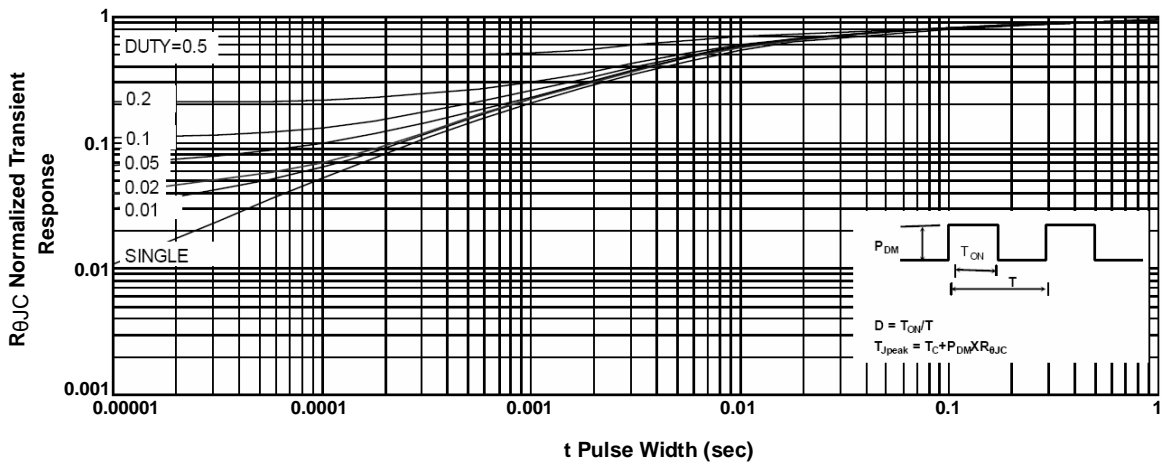


Fig.9 Normalized Maximum Transient Thermal Impedance

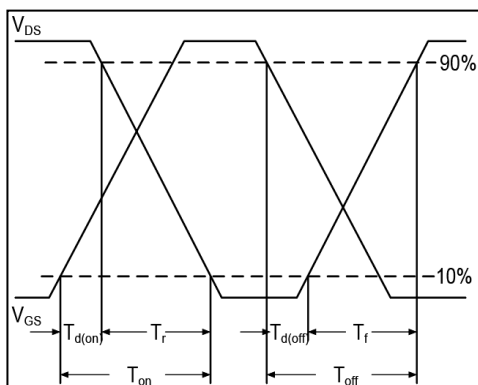


Fig.10 Switching Time Waveform

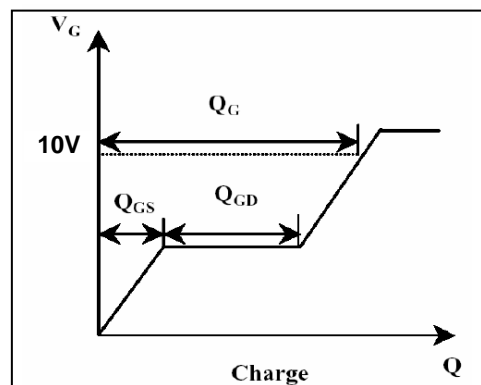


Fig.11 Unclamped Inductive Switching Waveform